Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | WATANABE ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,137,868	10-2000	Leach, Mark A.	379/106.01
	В	US-2003/0112652	06-2003	Shimada et al.	365/154
	С	US-6,822,764	11-2004	Okabe et al.	358/442
	D	US-2002/0045425	04-2002	Takeda et al.	455/41
	Е	US-6,822,764	11-2004	Okabe et al.	358/442
	F	US-2004/0178775	09-2004	Watanabe et al.	323/234
	G	US-2003/0112652	06-2003	Shimada et al.	, 365/154
	Н	US-2005/0052681	03-2005	Kogi, Shinsuke	358/001.14
	I	US-2004/0246512	12-2004	Miyamoto, Ryosuke	358/001.13
	J	US-			,
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	7-283895	10-1995	Japan		HO4N 1/00
	0					
	Р					
	Q					
	R					
	s	_				
	Т					

NON-PATENT DOCUMENTS

_							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
ļ	٧						
	w.						
	х						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.